Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination)r	
10/728,596	ENMEI, TOSHIHARU		
Examiner	Art Unit		
VI IAV SHANKAD	2673		

	SEARCHED				
Class	Subclass	Date	Examiner		
345	156-158, 169, 173-179	1/7/2006	vs		
178	18.0107				
178	19.0106				
·					

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
SAME	AS ABOVE	1/7/2006	vs		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
INVENTOR NAME SEARCH	1/7/2006	, vs	
		ŕ	